

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants: Young Hoon Kwarik

Examiner: Emily Y. Chan

Serial No: 10/769,115

Group Art Unit: 2829

Filed: January 30, 2004

Docket: YOR920030625US1 (163-27)

For: CONTACTLESS CIRCUIT TESTING FOR ADAPTIVE WAFER PROCESSING

Mail Stop AF
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

AMENDMENT UNDER 37 C.F.R. §1.116

Sir:

This is a response to the Office Action mailed October 10, 2006. Please amend the above-identified application as follows:

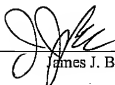
CERTIFICATE OF MAILING 37 C.F.R. §1.8(a)

I hereby certify that this correspondence (and any document referred to as being attached or enclosed) is being filed via Private Pair, addressed to: Mail Stop AF, Commissioner for Patents, P.O. Box 1450, Alexandria, VA

22313-1450

on

12/19/06


James J. Bitetto